INTER CLAIMED G O 9 G G G G G G G G G			Application/Control No.	Applicant	Applicant(s)/Patent under Reexamination
	Issue Classifica	tion	09766022	EFTEKHA	RI, JAMSHID
Subclass					
Nguyen, Jannifer T 2629			Examiner	Art Unit	
ORIGINAL INTERNATIONAL CLASSIFICATION			Nguyen, Jennifer T	2629	
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Total Claims All RICHARD HJERPE 30 SUPERVISORY PATENT EXAMINER 30 30 30 30 30 30 30 3					
(Date) SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2600 aminer) (Date) (Primary Examiner) (Date) (MS/A) (Date) (Date) (Date) (Date) (Date)	Jennifer T Mguyem	11/11/06	M. Mal		Total Claims Allowed:
O.G. (Date) (Primary Examiner) (Date) (MS) (Bate) (Date) ((Assistant Examiner)	(Date)	SUPERVISORY PATENT EXAMIN	VER	30
(Date) (Primary Examiner) (Date) 1	Willed Stran 11	90-61-1	TECHNOLOGY CENTER 2600		
	(Legal Instruments Examiner)	(Date)	(Primary Examiner)	(Date) 11/5/86	2

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